


<b>Search Notes</b>  	<b>Application/Control No.</b>  10577325	<b>Applicant(s)/Patent Under Reexamination</b>  NAKAMURA ET AL.
	<b>Examiner</b>  Wilson, Bryan E	<b>Art Unit</b>  2891

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Keyword search in 257/40 and 438/99	10-24-2007	BW
STIC database search STN for chemical structures	10-23-2007	BW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner